

<b>Notice of References Cited</b>	Application/Control No. 10/520,901	Applicant(s)/Patent Under Reexamination FUJIWARA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	PCT/US01/27127 (page1-2)	03-2002	WO 02/20754	Stuart et al.	C12N 15/00
	O	PCT/EP00/00265 (page 1)	07-2000	WO 00/42208	Nemerow et al.	C12N 15/85
	P	PCT/US00/00390 (page 1)	07-2000	WO 00/40741	Arya et al.	C12N 15/867
	Q	PCT/EP98/08216 (page 1)	07-1999	WO 99/33998	Hagen et al.	C12N 15/54
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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